

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	50194	(Cu or copper) and (cap or capping)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/04 13:03
L2	13971	1 and (oxidiz\$6 or oxidat\$6 or CuO or Cu2O or ((Cu or copper or cupric) adj oxide))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/04 13:04
L3	6483	1 and (CMP or polish\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/04 13:04
L4	3260	3 and 2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/04 13:05
L5	3205	4 and (@ad<="20040128" or @rlad<="20040128")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/04 13:06
L6	2312	5 and semiconductor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/04 13:06
L7	2109	6 and (strength or hardness or nitrid\$6 or boroniz\$6 or phosphorat\$6 or CuN or CuP or CuB)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/04 13:08

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)



 Welcome  
 United States Patent and Trademark Office

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Tables of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

**IEEE Enterprise**

- ☐ Access the IEEE Enterprise File Cabinet

**Try our New Full-text Search Prototype**
**GO**
[Help](#)

- 1) Enter a single keyword, phrase, or Boolean expression.  
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.

Example: optical &lt;and&gt; (fiber &lt;or&gt; fibre) &lt;in&gt; ti

- 3) Limit the results by selecting Search Options.

- 4) Click Search. See [Search Examples](#)

(cu\* or copper\*) and (cmp or polish\*) and (cap or capping or nitrid\* or boron\* or phosphorat\* or cun or cup or

**Start Search**
**Clear**

Note: This function returns plural and suffixed forms of the keyword(s).

 Search operators: <and> <or> <not> <in> [More](#)

 Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)
**Search Options:**
**Select publication types:**

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

**Select years to search:**

 From year:  to 
**Organize search results by:**

 Sort by: 

 In:  order

 List  Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved